



Advanced X-ray Instrumentation, Optics and Metrology

24th January 2023

Only in-person meeting

Location: Building 28c, 2nd floor / Room Seminar room Flash
(DESY, Notkestraße 85, 22607 Hamburg)

Organiser: Maurizio Vannoni, Liubov Samoylova

Contact: maurizio.vannoni@xfel.eu

Date			
9:00-9:10	Welcome and Satellite remarks	Maurizio Vannoni	European XFEL
9:10-9:40	Instrumentation at the LCLS Metrology Laboratory – from LCLS-II to LCLS-II-HE, and beyond	May Ling	LCLS
9:40-10:10	Current thin-film developments for X-ray mirrors at Hereon	Michael Störmer	Helmholtz Zentrum Hereon
10:10-10:40	coffee break		
10:40-11:05	Wavefront metrology and refractive optics characterisation at the ESRF	Rafael Celestre	ESRF
11:05-11:30	Temporal diagnostics of X-ray FELs using split-delay optics at SACLA	Taito Osaka	SACLA
11:30-11:55	A diamond channel cut monochromator for intense MHz repetition rate operation at EuXFEL: first experimental results	Kelin Tasca	European XFEL
12:00-13:10	Lunch break		
13:10-13:50	Reflective and diffractive X-ray optical elements for SR- and FEL-application and their characterization by means of ex- situ and at-wave-length metrology	Frank Siewert	Helmholtz Zentrum Berlin
13:50-14:15	Pushing the limits in diffractive optics for XFEL applications	Talgat Mamyrbayev	PSI
14:15-14:45	Coffee break		
14:45-15:10	SwissFEL beamline designs and commissioning results	Rolf Follath	PSI
15:10-15:35	Performance analysis of x-ray Optical Delay Line at European XFEL	Marziyeh Tavakkoly	European XFEL
15:35-16:00	High-heat-load and high-resolution monochromators at LCLS-II-HE: Advances in wavefront preserving crystal optics	Hasan Yavas	LCLS
16:00-17:00	roundtable and closing session		